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Studies on Correlation and Path Analysis for Spot Blotch Disease Resistance and Yield Parameters in F2 Segregating Population of Durum Wheat (*Triticum durum* L.)

C.K. Chethana¹, V. Rudranaik^{1*}, S.A. Desai², S.S. Biradar¹, Y. Narendra Kadoo³, I.K. Kalappanavar⁴ and B.N. Aravindkumar⁵

¹AICRP on Wheat, Main Agricultural Research Station, University of Agricultural Sciences Dharwad - 580 005, Karnataka, India

²Protection of Plant Varieties and Farmer's Right Authority (PPV & FRA), PUSA, New Delhi-110012, India)

³Biochemical Sciences Division, CSIR-National Chemical Laboratory, Pune, Maharashtra, India

⁴Department of Plant Pathology



Dr. M. Prakash
Editor-in-chief

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